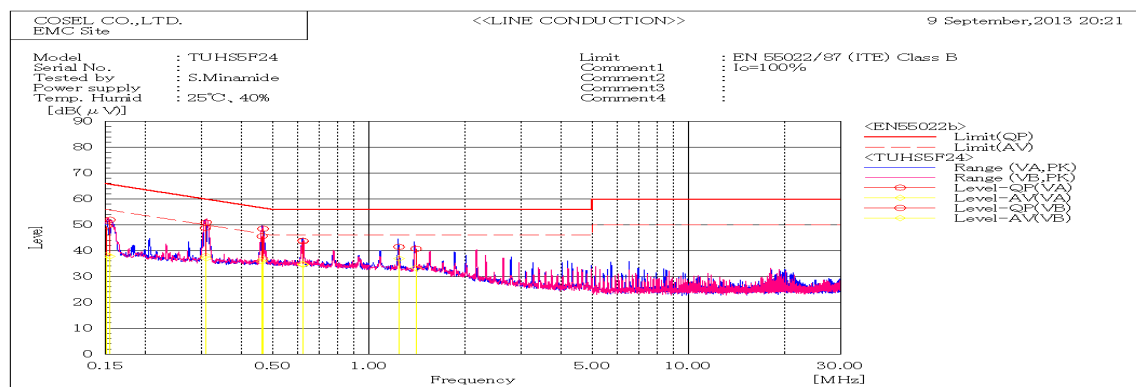
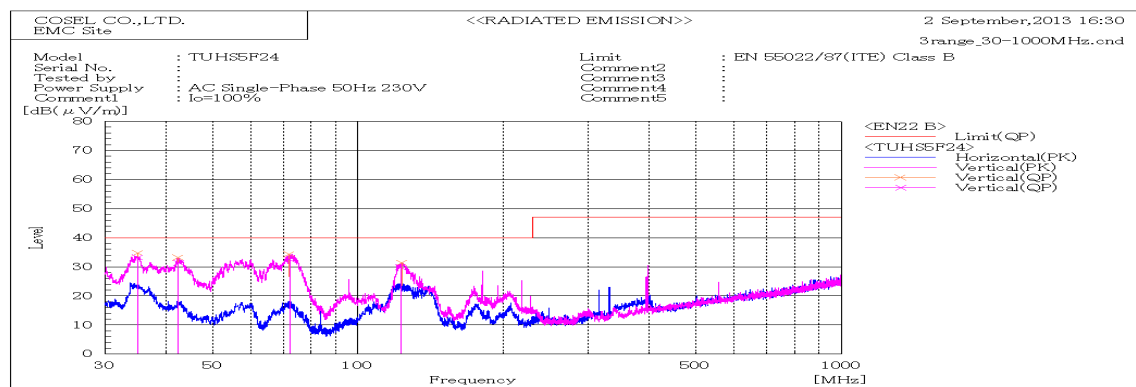


DATA SHEET

DATA SHEET		Date	16-Dec-13
Model	TUHS5F24	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide



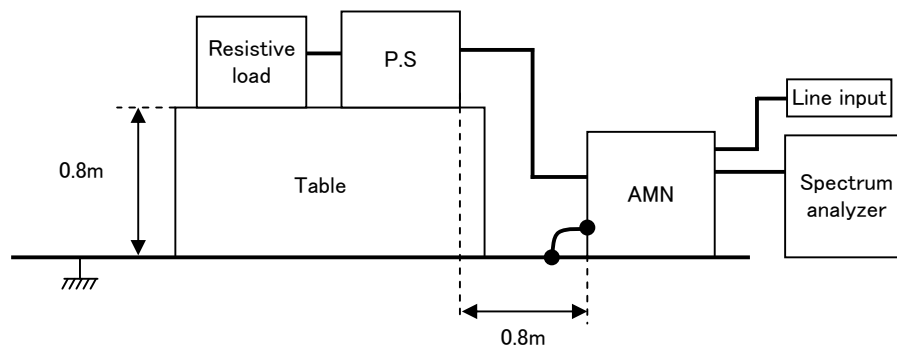
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.15519		VA	31.7	17.5	20.3	52	37.8	65.7	55.7	13.7	17.9	Pass	
0.15132		VB	29.3	18	20.2	49.5	38.2	65.9	55.9	16.4	17.7	Pass	
0.30994		VA	30.8	17	20.1	50.9	37.1	60	50	9.1	12.9	Pass	
0.30827		VB	28.7	17.9	20.1	48.8	38	60	50	11.2	12	Pass	
0.46717		VA	28.4	16.7	20.1	48.5	36.8	56.6	46.6	8.1	9.8	Pass	
0.46387		VB	25.5	15.7	20.1	45.6	35.8	56.6	46.6	11	10.8	Pass	
0.62283		VA	23.6	14.5	20.1	43.7	34.6	56	46	12.3	11.4	Pass	
0.62228		VB	23.8	14.7	20.1	43.9	34.8	56	46	12.1	11.2	Pass	
1.24385		VA	21.3	16.8	20.2	41.5	37	56	46	14.5	9	Pass	
1.40518		VB	20.5	13.1	20.2	40.7	33.3	56	46	15.3	12.7	Pass	



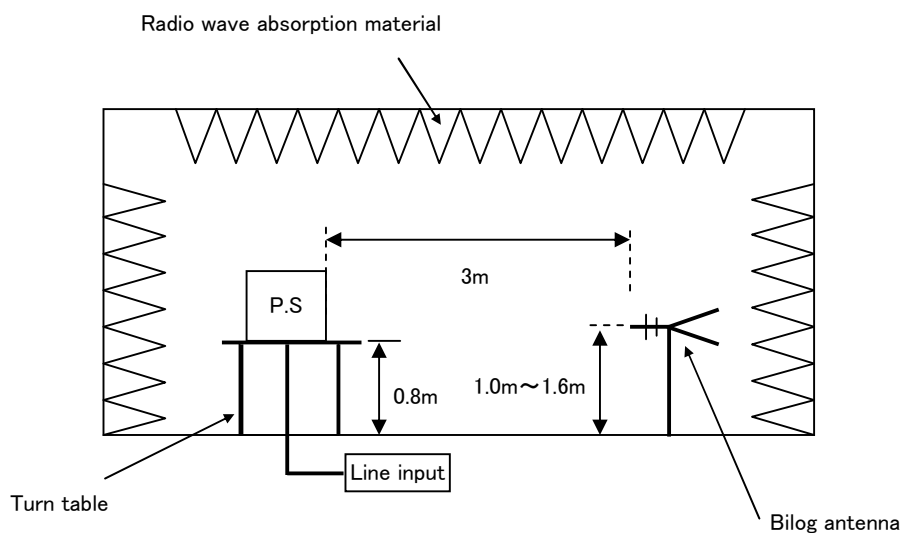
Frequency MHz	Polariz ation	Stabilit y	Reading dB(μV)		Factor dB(1/m)	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP			QP							
34.992	V	Stable	48.1	-14.8		33.3		40	6.7	Pass	105	36	
42.467	V	Stable	48	-16.6		31.4		40	8.6	Pass	107	41	
72.229	V	Stable	53.1	-20.6		32.5		40	7.5	Pass	134	209	
122.509	V	Stable	46.8	-17		29.8		40	10.2	Pass	114	8	

DATA SHEET		Date	16-Dec-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide

1. Line conduction



2. Radiated emission



Conditions

Test: EMI

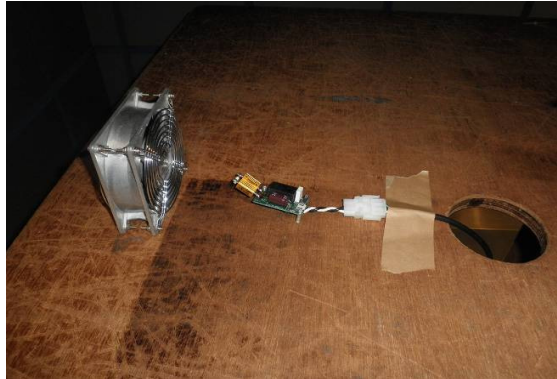
Model Name: TUHS5F□□

○ Photographs of Test Set-Up

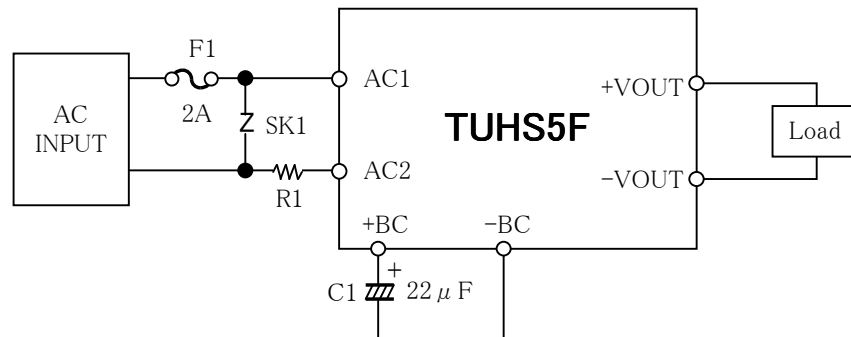
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



F1: SLT250V2A (Nippon Seisen) 2A
 R1: 1K100JA (TAMURA THERMAL DEVICE) 10Ω
 SK1: TND10V-511K (NIPPON CHEMI-CON)

Fig.1 Testing circuitry